



**THE DATASHEET OF
C3M0021120K**

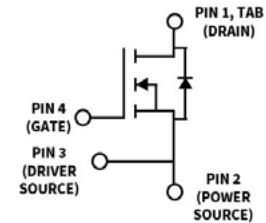
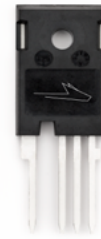


C3M0021120K

Silicon Carbide Power MOSFET
C3M™ MOSFET Technology
N-Channel Enhancement Mode

Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- 8mm of creepage distance between drain and source
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant



Part Number	Package	Marking
C3M0021120K	TO 247-4	C3M0021120K

Applications

- Solar inverters
- EV motor drive
- High voltage DC/DC converters
- Switched mode power supplies
- Load switch

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

Key Parameters

Parameter	Symbol	Min.	Typ.	Max	Unit	Conditions	Note
Drain - Source Voltage	V_{DS}			1200	v	$T_c = 25^\circ\text{C}$	
Maximum Gate - Source Voltage	$V_{GS(max)}$	-8		+19		Transient	
Operational Gate-Source Voltage	$V_{GS op}$		-4/15			Static	Note 1
DC Continuous Drain Current	I_D			100	A	$V_{GS} = 15\text{ V}, T_c = 25^\circ\text{C}, T_J \leq 175^\circ\text{C}$	Fig. 19 Note 2
				74		$V_{GS} = 15\text{ V}, T_c = 100^\circ\text{C}, T_J \leq 175^\circ\text{C}$	
Pulsed Drain Current	I_{DM}			200		t_{Pmax} limited by T_{Jmax} $V_{GS} = 15\text{ V}, T_c = 25^\circ\text{C}$	Fig. 22
Power Dissipation	P_D			469	W	$T_c = 25^\circ\text{C}, T_J = 175^\circ\text{C}$	Fig. 20
Operating Junction and Storage Temperature	T_J, T_{stg}			-40 to +175	$^\circ\text{C}$		
Solder Temperature	T_L			260		According to JEDEC J-STD-020	
Mounting Torque	M_D			1	Nm lbf-in	M3 or 6-32 screw	
				8.8			

Note (1): Recommended turn-on gate voltage is 15V with $\pm 5\%$ regulation tolerance, see Application Note PRD-04814 for additional details

Note (2): Verified by design


Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

	Symbol	Min.	Typ.	Max.	Unit	Test Conditions	Note
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	1200	—	—		$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
Gate Threshold Voltage	$V_{GS(th)}$	1.8	2.5	3.6	V	$V_{DS} = V_{GS}, I_D = 17.7\ \text{mA}$	Fig. 11
		—	2.0	—		$V_{DS} = V_{GS}, I_D = 17.7\ \text{mA}, T_J = 175^\circ\text{C}$	
Zero Gate Voltage Drain Current	I_{DSS}	—	1	50	nA	$V_{DS} = 1200\ \text{V}, V_{GS} = 0\ \text{V}$	
Gate-Source Leakage Current	I_{GSS}	—	10	250	nA	$V_{GS} = 15\ \text{V}, V_{DS} = 0\ \text{V}$	
Drain-Source On-State Resistance	$R_{DS(on)}$	—	21	28.8	m Ω	$V_{GS} = 15\ \text{V}, I_D = 50\ \text{A}$	Fig. 4, 5, 6
		—	38	—		$V_{GS} = 15\ \text{V}, I_D = 50\ \text{A}, T_J = 175^\circ\text{C}$	
Transconductance	g_{fs}	—	35	—	S	$V_{DS} = 20\ \text{V}, I_{DS} = 50\ \text{A}$	Fig. 7
		—	33	—		$V_{DS} = 20\ \text{V}, I_{DS} = 50\ \text{A}, T_J = 175^\circ\text{C}$	
Input Capacitance	C_{iss}	—	4818	—	pF	$V_{GS} = 0\ \text{V}, V_{DS} = 1000\ \text{V}$ $f = 100\ \text{kHz}$ $V_{AC} = 25\ \text{mV}$	Fig. 17, 18
Output Capacitance	C_{oss}	—	180	—			
Reverse Transfer Capacitance	C_{rss}	—	12	—			
C_{oss} Stored Energy	E_{oss}	—	99	—			μJ
Turn-On Switching Energy (SiC Diode FWD)	E_{on}	—	0.69	—	mJ	$V_{DS} = 800\ \text{V}, V_{GS} = -4\ \text{V}/+15\ \text{V}, I_D = 50\ \text{A},$ $R_{G(ext)} = 2.5\ \Omega, L = 157\ \mu\text{H},$ $T_J = 175^\circ\text{C}$	Fig. 26, 29
Turn Off Switching Energy (SiC Diode FWD)	E_{off}	—	0.42	—			
Turn-On Switching Energy (Body Diode FWD)	E_{on}	—	1.58	—			
Turn Off Switching Energy (Body Diode FWD)	E_{off}	—	0.34	—			
Turn-On Delay Time	$t_{d(on)}$	—	29	—	ns	$V_{DD} = 800\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $R_{G(ext)} = 2.5\ \Omega, L = 157\ \mu\text{H}$ Timing relative to V_{DS} inductive load	Fig. 27
Rise Time	t_r	—	33	—			
Turn-Off Delay Time	$t_{d(off)}$	—	57	—			
Fall Time	t_f	—	14	—			
Internal Gate Resistance	$R_{G(int)}$	—	3.3	—	Ω	$f = 1\ \text{MHz}, V_{AC} = 25\ \text{mV}$	
Gate to Source Charge	Q_{gs}	—	49	—	nC	$V_{DS} = 800\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 50\ \text{A}$ Per IEC60747-8-4 pg 21	Fig. 12
Gate to Drain Charge	Q_{gd}	—	50	—			
Total Gate Charge	Q_g	—	162	—			

Note (3): $C_{o(er)}$, a lumped capacitance that gives the same stored energy as C_{oss} while V_{ds} is rising from 0 to 800V
 $C_{o(tr)}$, a lumped capacitance that gives the same stored time as C_{oss} while V_{ds} is rising from 0 to 800V



Reverse Diode Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Typ.	Max.	Unit	Test Conditions	Notes
Diode Forward Voltage	V_{SD}	4.6	—	V	$V_{GS} = -4\text{ V}, I_{SD} = 25\text{ A}, T_J = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.2	—		$V_{GS} = -4\text{ V}, I_{SD} = 25\text{ A}, T_J = 175^\circ\text{C}$	
Continuous Diode Forward Current	I_S	—	90	A	$V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$	
Diode pulse Current	$I_{S, pulse}$	—	200		$V_{GS} = -4\text{ V}$, pulse width t_p limited by T_{Jmax}	
Reverse Recover Time	t_{rr}	34	—	ns	$V_{GS} = -4\text{ V}, I_{SD} = 50\text{ A}, V_R = 800\text{ V}$ $dif/dt = 2600\text{ A}/\mu\text{s}, T_J = 175^\circ\text{C}$	
Reverse Recovery Charge	Q_{rr}	928	—			
Peak Reverse Recovery Current	I_{RRM}	42	—	nC		

Thermal Characteristics

Parameter	Symbol	Typ.	Unit	Note
Thermal Resistance from Junction to Case	$R_{\theta JC}$	0.32	$^\circ\text{C}/\text{W}$	Fig. 21
Thermal Resistance From Junction to Ambient	$R_{\theta JA}$	40		



Typical Performance

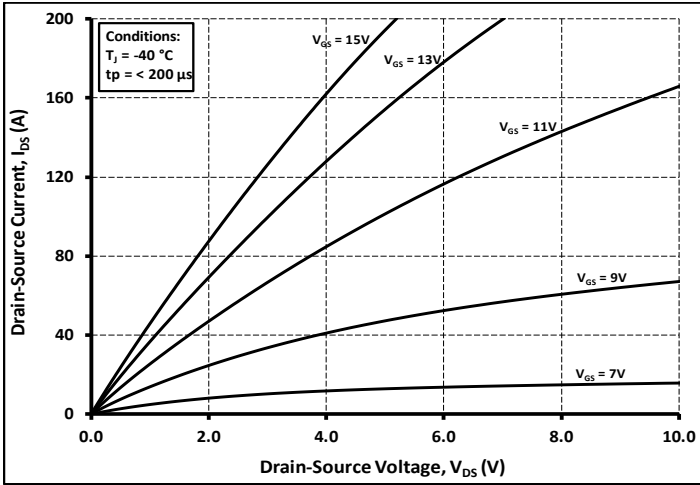


Figure 1. Output Characteristics $T_j = -40^\circ\text{C}$

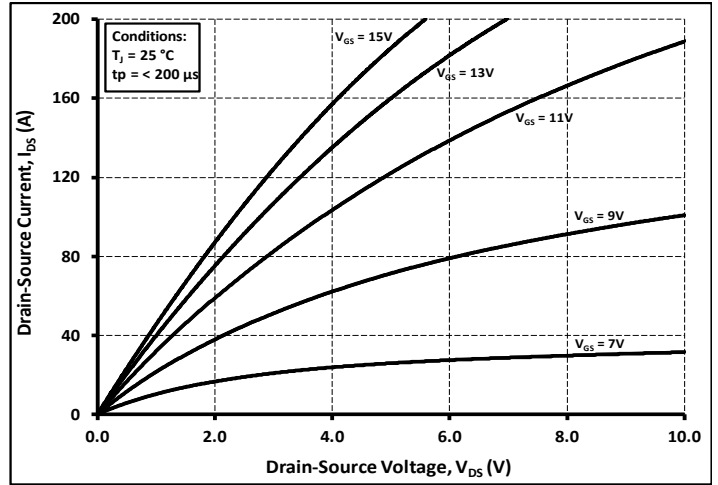


Figure 2. Output Characteristics $T_j = 25^\circ\text{C}$

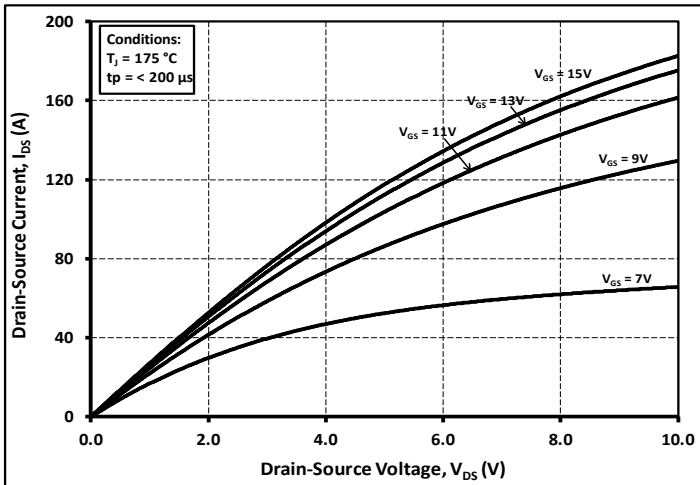


Figure 3. Output Characteristics $T_j = 175^\circ\text{C}$

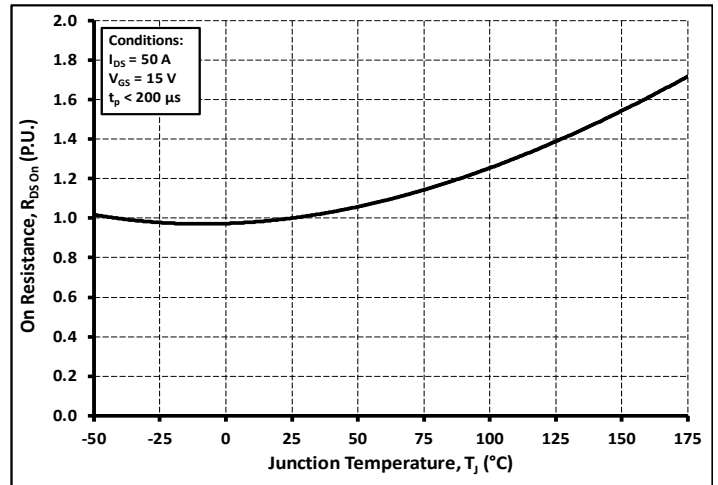


Figure 4. Normalized On-Resistance vs. Temperature

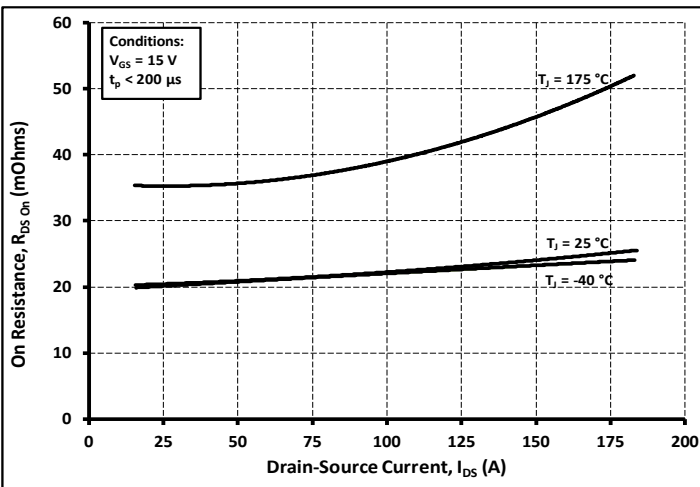


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

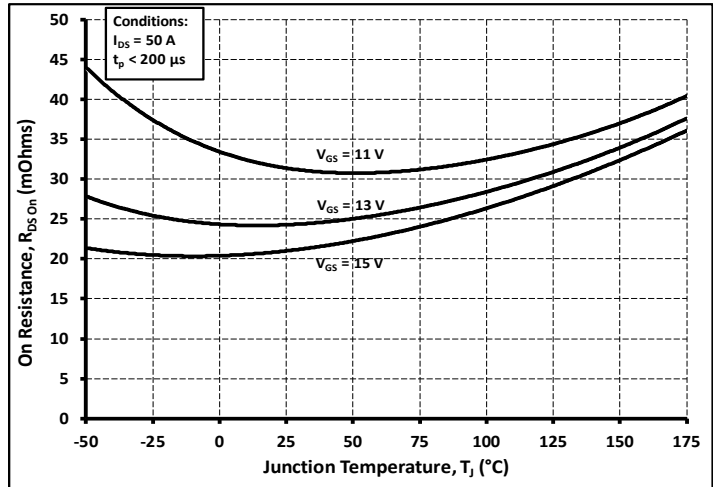


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage



Typical Performance

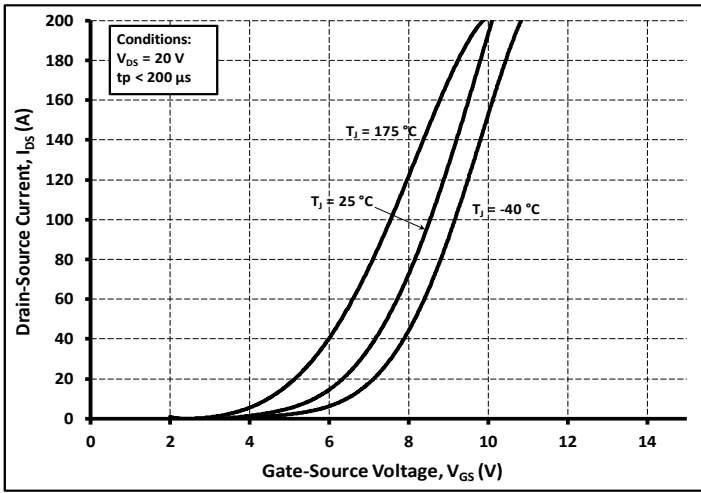


Figure 7. Transfer Characteristic for Various Junction Temperatures

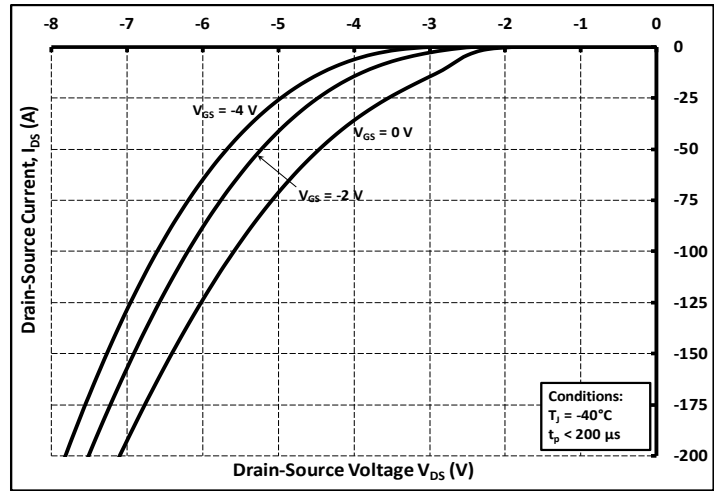


Figure 8. Body Diode Characteristic at -40 °C

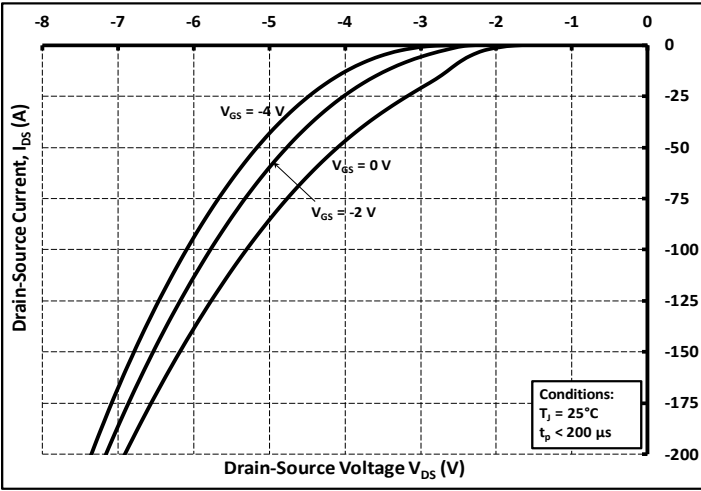


Figure 9. Body Diode Characteristic at 25 °C

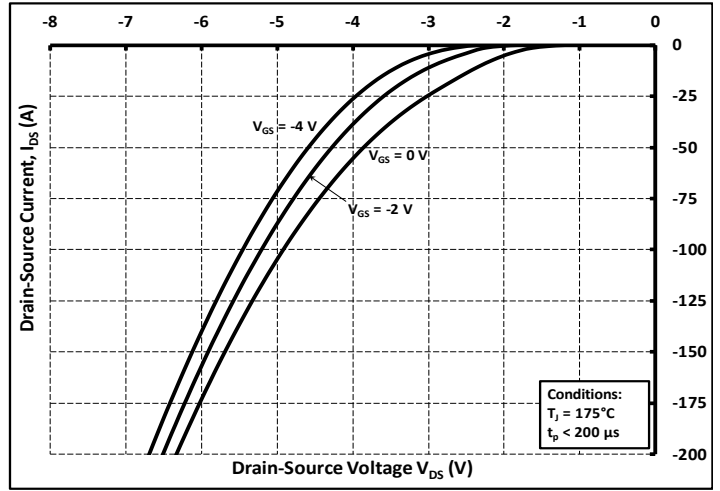


Figure 10. Body Diode Characteristic at 175 °C

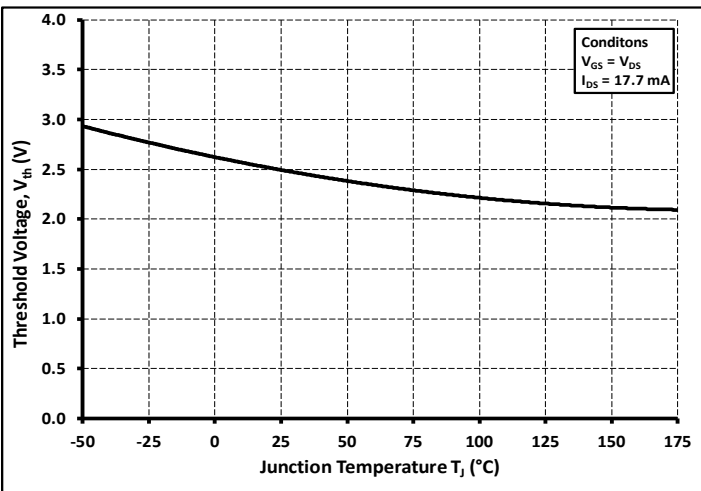


Figure 11. Threshold Voltage vs. Temperature

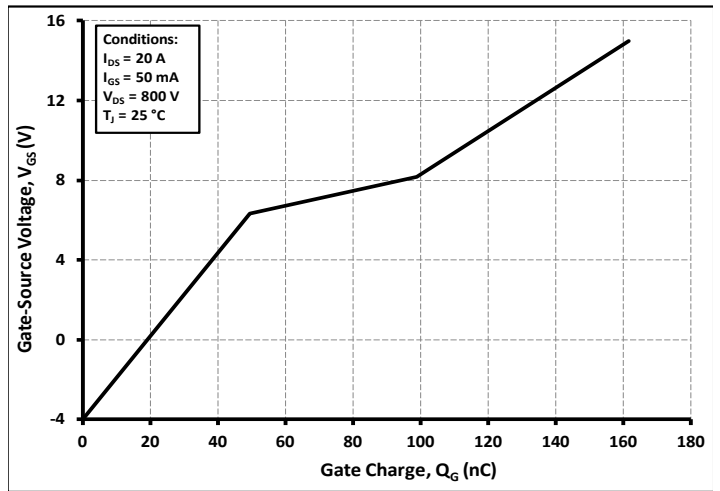


Figure 12. Gate Charge Characteristics



Typical Performance

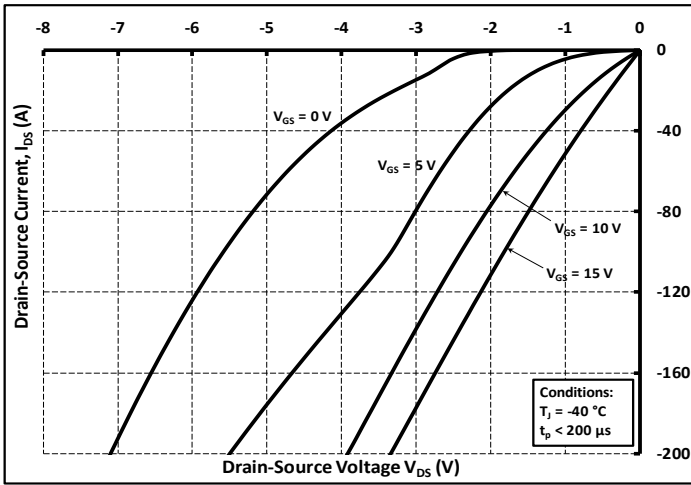


Figure 13. 3rd Quadrant Characteristic at -40°C

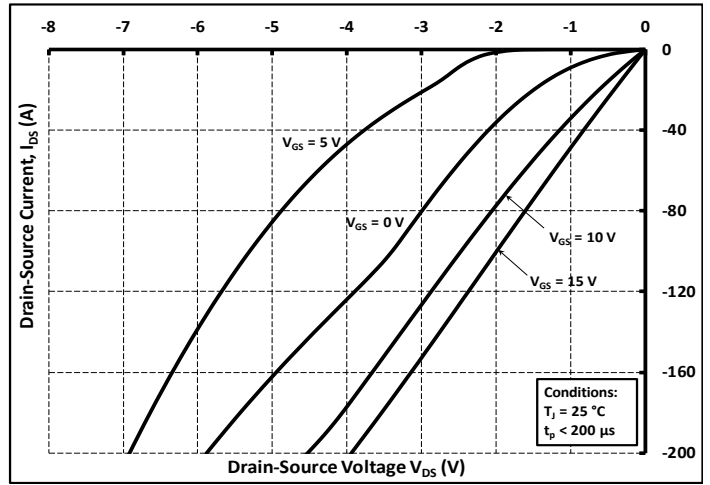


Figure 14. 3rd Quadrant Characteristic at 25°C

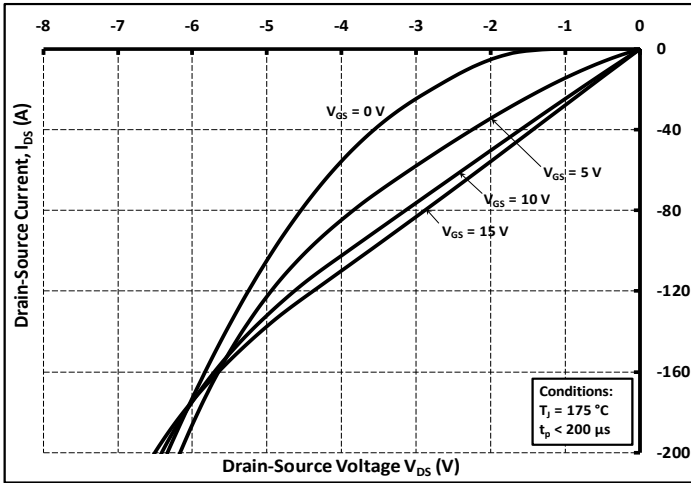


Figure 15. 3rd Quadrant Characteristic at 175°C

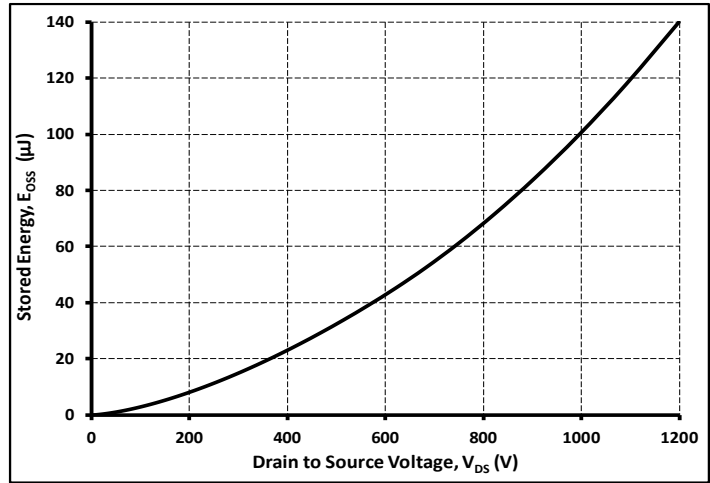


Figure 16. Output Capacitor Stored Energy

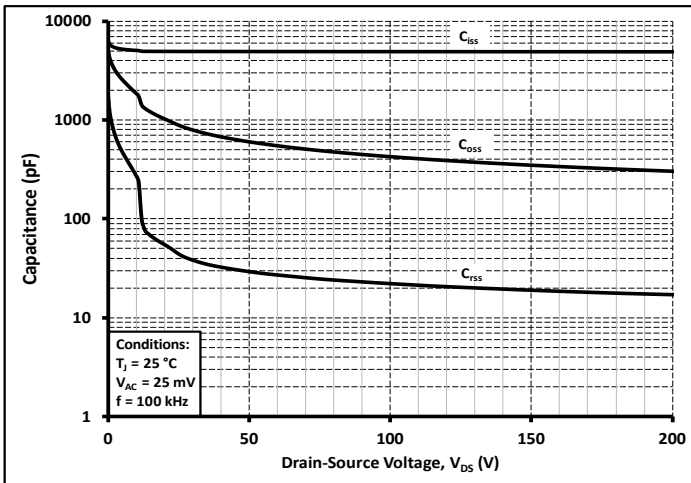


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

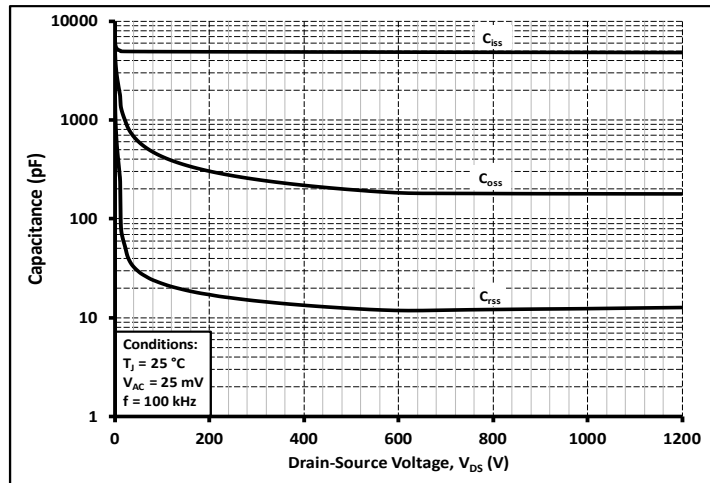


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1200V)



Typical Performance

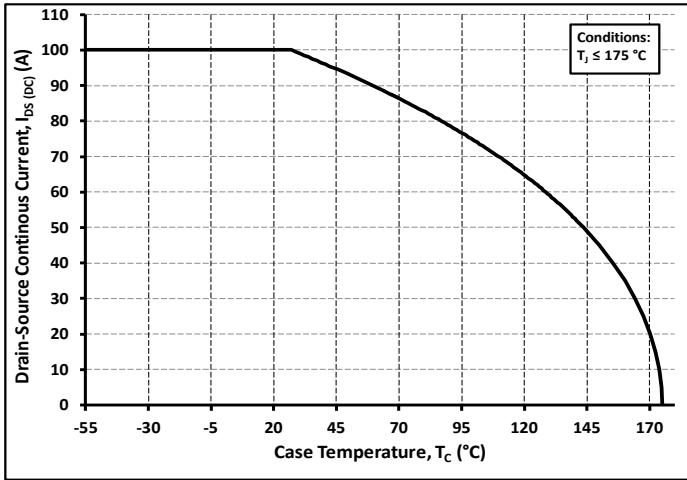


Figure 19. Continuous Drain Current Derating vs. Case Temperature

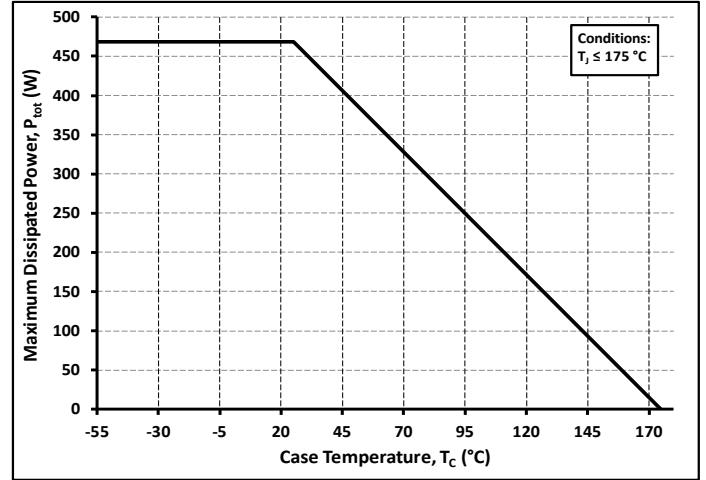


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

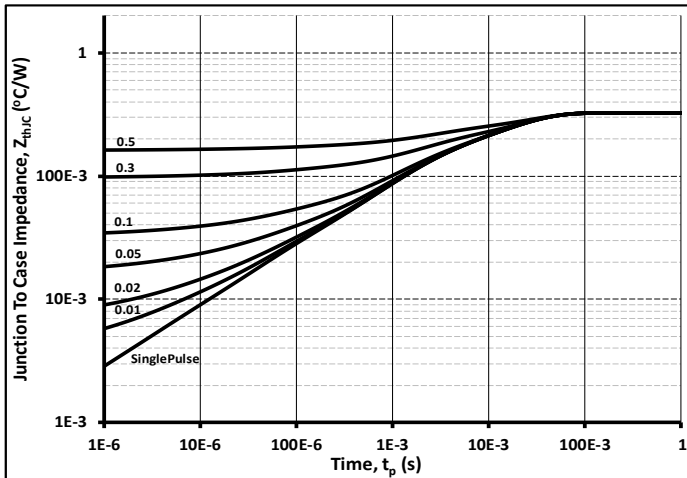


Figure 21. Transient Thermal Impedance (Junction - Case)

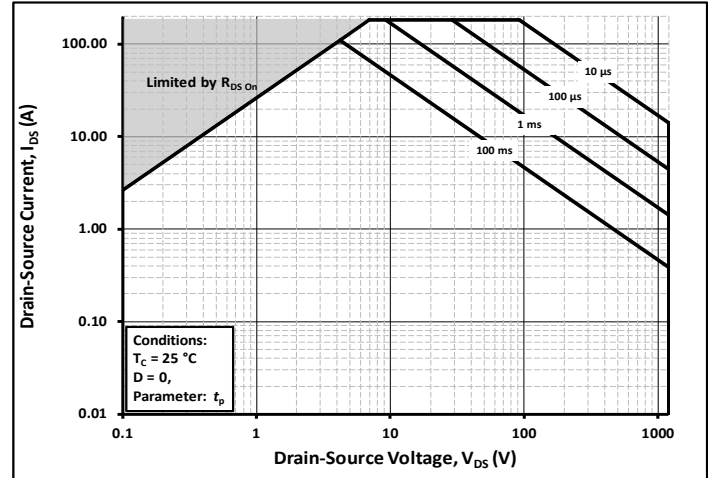


Figure 22. Safe Operating Area

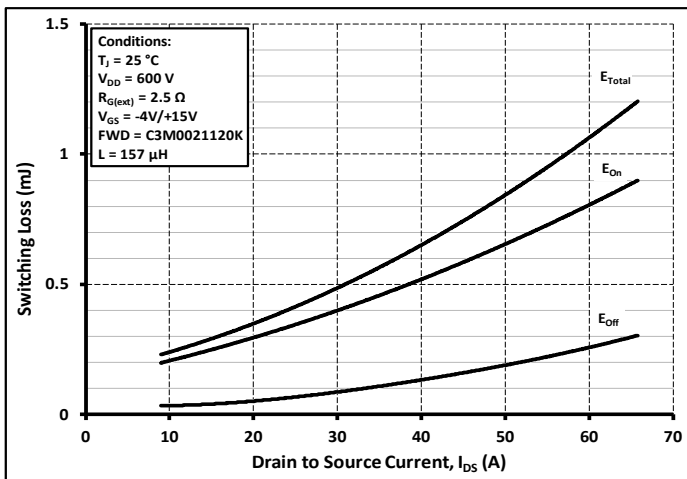


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 600 V$)

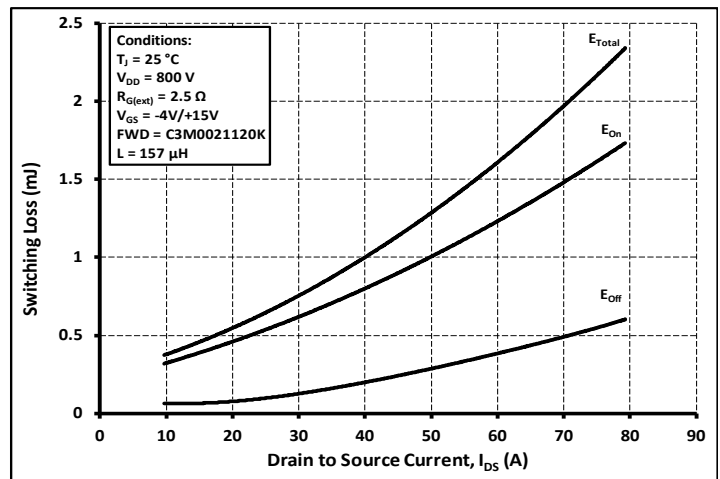


Figure 24. Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 800 V$)

Typical Performance

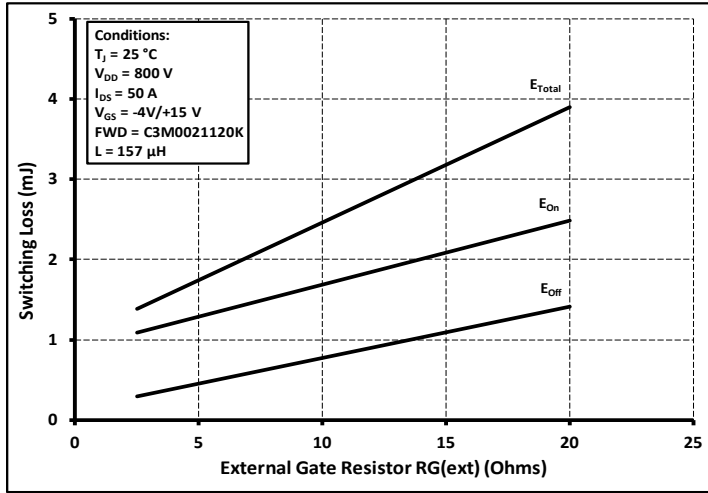


Figure 25. Clamped Inductive Switching Energy vs. $R_{G(ext)}$

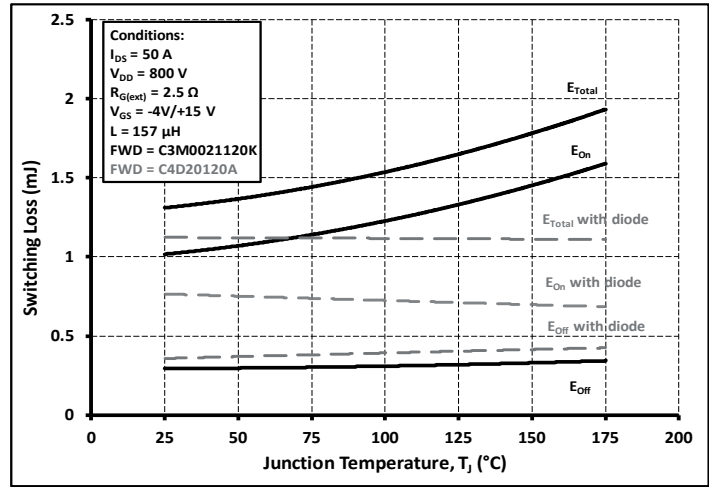


Figure 26. Clamped Inductive Switching Energy vs. Temperature

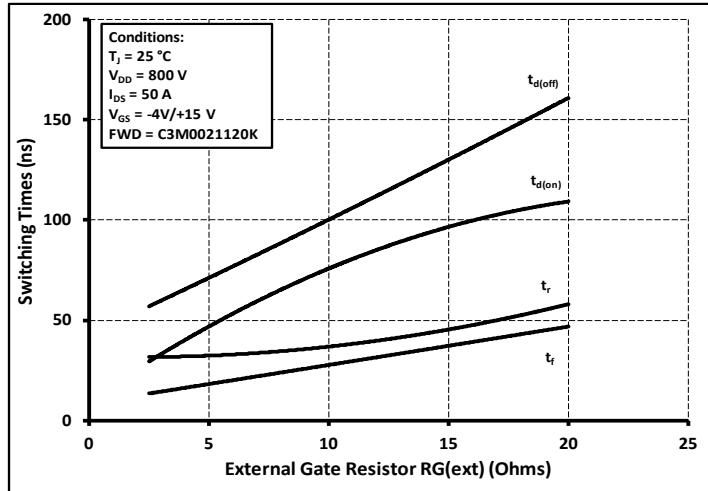


Figure 27. Switching Times vs. $R_{G(ext)}$

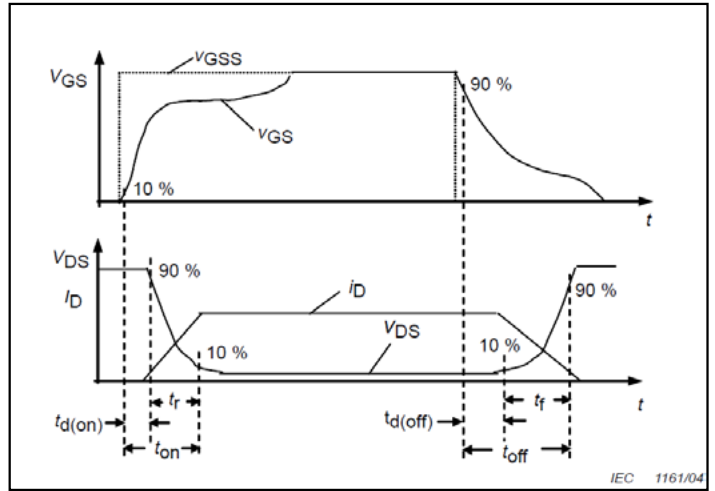


Figure 28. Switching Times Definition

Test Circuit Schematic¹

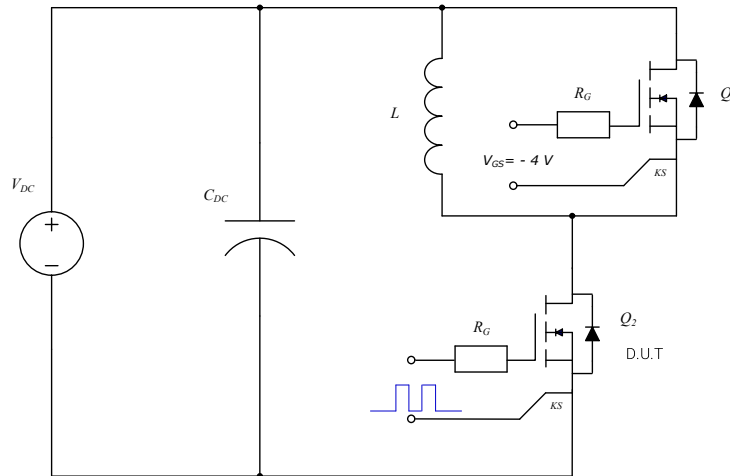
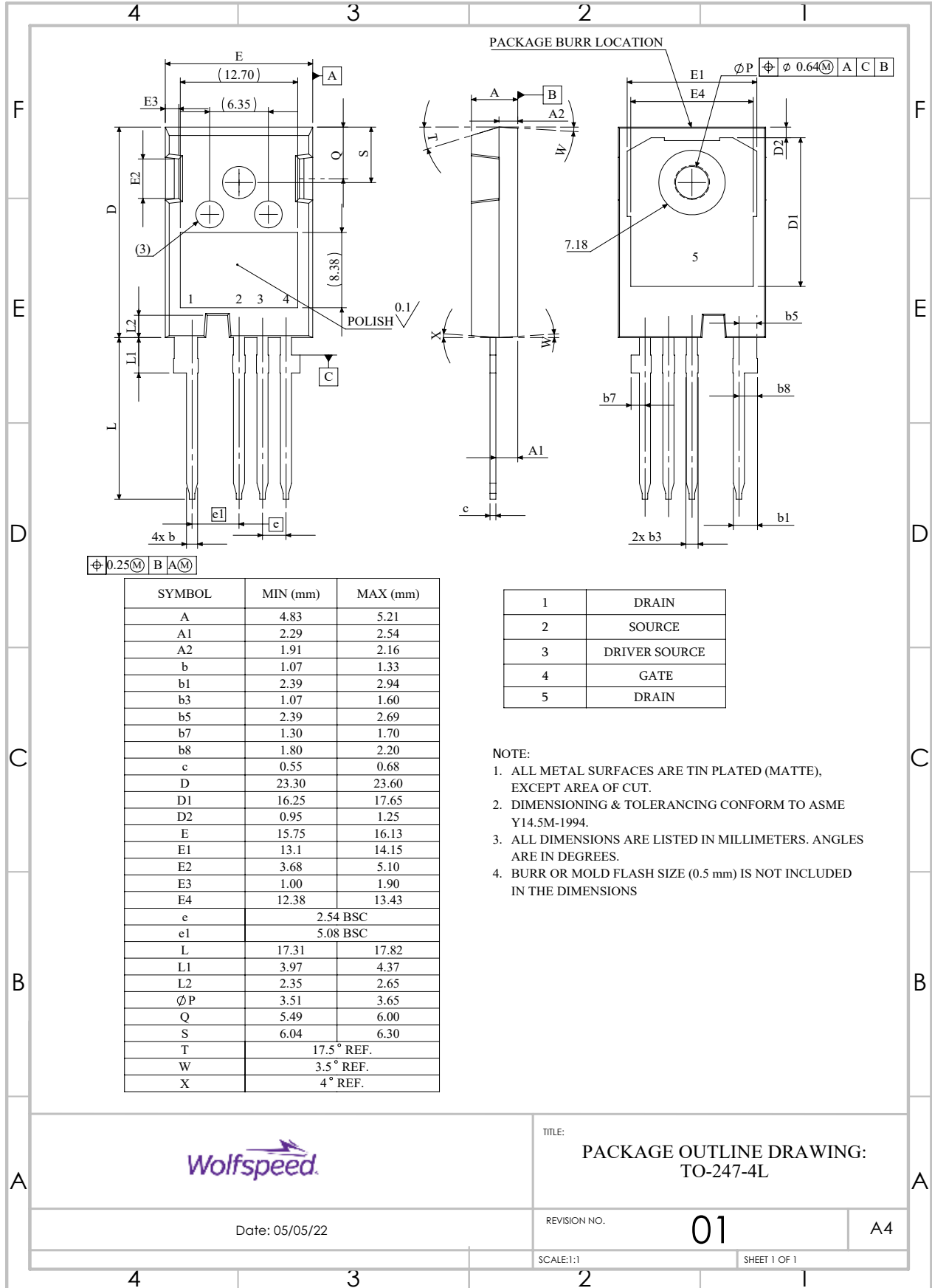


Figure 29. Clamped Inductive Switching Waveform Test Circuit

Note:

¹ Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.

Package Dimensions – Package TO-247-4L



TITLE:
PACKAGE OUTLINE DRAWING:
TO-247-4L

Date: 05/05/22

REVISION NO.

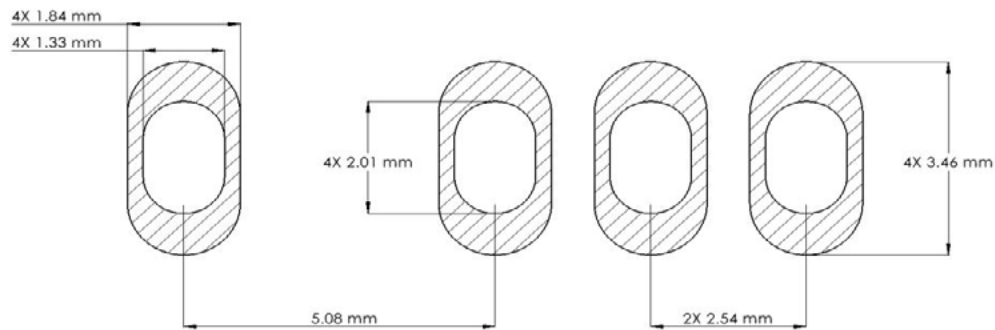
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SCALE:1:1

SHEET 1 OF 1

Recommended Solder Pad Layout



Revision History

Document Version	Date of Release	Description of Changes
1	March-2023	N/A
2	December-2023	Updated Package Image, solder pad layout, added revision history, Table 1 layout revised



Notes & Disclaimer

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The Silicon Carbide MOSFET module switches at speeds beyond what is customarily associated with IGBT-based modules. Therefore, special precautions are required to realize optimal performance. The interconnection between the gate driver and module housing needs to be as short as possible. This will afford optimal switching time and avoid the potential for device oscillation. Also, great care is required to insure minimum inductance between the module and DC link capacitors to avoid excessive VDS overshoot.

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Wolfspeed representative or from the Product Documentation sections of www.wolfspeed.com.

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